

Welcome to [E-XFL.COM](https://www.e-xfl.com)

### Understanding [Embedded - CPLDs \(Complex Programmable Logic Devices\)](#)

Embedded - CPLDs, or Complex Programmable Logic Devices, are highly versatile digital logic devices used in electronic systems. These programmable components are designed to perform complex logical operations and can be customized for specific applications. Unlike fixed-function ICs, CPLDs offer the flexibility to reprogram their configuration, making them an ideal choice for various embedded systems. They consist of a set of logic gates and programmable interconnects, allowing designers to implement complex logic circuits without needing custom hardware.

### Applications of Embedded - CPLDs

#### Details

Product Status	Obsolete
Programmable Type	In System Programmable
Delay Time tpd(1) Max	3.5 ns
Voltage Supply - Internal	2.375V ~ 2.625V
Number of Logic Elements/Blocks	4
Number of Macrocells	64
Number of Gates	1250
Number of I/O	68
Operating Temperature	0°C ~ 70°C (TA)
Mounting Type	Surface Mount
Package / Case	100-LBGA
Supplier Device Package	100-FBGA (11x11)
Purchase URL	<a href="https://www.e-xfl.com/product-detail/intel/epm7064bfc100-3">https://www.e-xfl.com/product-detail/intel/epm7064bfc100-3</a>

MAX 7000B devices provide programmable speed/power optimization. Speed-critical portions of a design can run at high speed/full power, while the remaining portions run at reduced speed/low power. This speed/power optimization feature enables the designer to configure one or more macrocells to operate up to 50% lower power while adding only a nominal timing delay. MAX 7000B devices also provide an option that reduces the slew rate of the output buffers, minimizing noise transients when non-speed-critical signals are switching. The output drivers of all MAX 7000B devices can be set for 3.3 V, 2.5 V, or 1.8 V and all input pins are 3.3-V, 2.5-V, and 1.8-V tolerant, allowing MAX 7000B devices to be used in mixed-voltage systems.

MAX 7000B devices are supported by Altera development systems, which are integrated packages that offer schematic, text—including VHDL, Verilog HDL, and the Altera Hardware Description Language (AHDL)—and waveform design entry, compilation and logic synthesis, simulation and timing analysis, and device programming. Altera software provides EDIF 2.0.0 and 3.0.0, LPM, VHDL, Verilog HDL, and other interfaces for additional design entry and simulation support from other industry-standard PC- and UNIX-workstation-based EDA tools. Altera software runs on Windows-based PCs, as well as Sun SPARCstation, and HP 9000 Series 700/800 workstations.



For more information on development tools, see the *MAX+PLUS II Programmable Logic Development System & Software Data Sheet* and the *Quartus Programmable Logic Development System & Software Data Sheet*.

## Functional Description

The MAX 7000B architecture includes the following elements:

- LABs
- Macrocells
- Expander product terms (shareable and parallel)
- PIA
- I/O control blocks

The MAX 7000B architecture includes four dedicated inputs that can be used as general-purpose inputs or as high-speed, global control signals (clock, clear, and two output enable signals) for each macrocell and I/O pin. [Figure 1](#) shows the architecture of MAX 7000B devices.

## Expander Product Terms

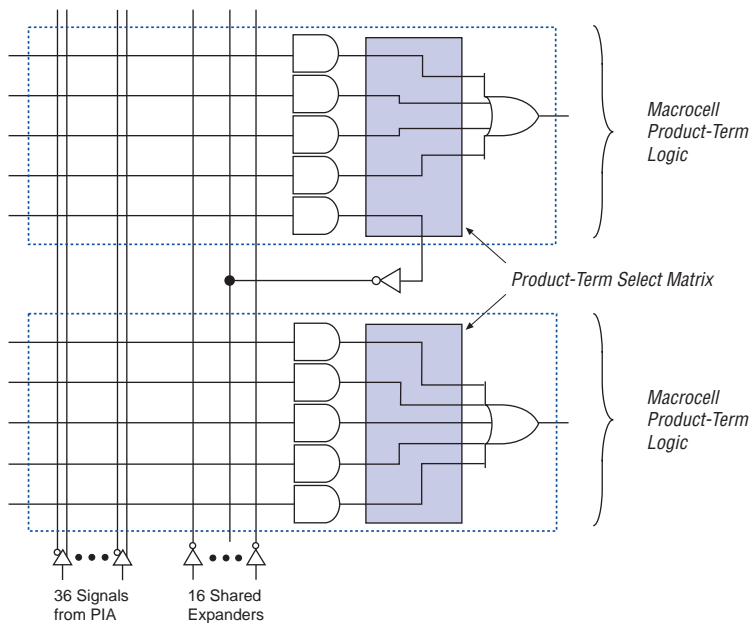
Although most logic functions can be implemented with the five product terms available in each macrocell, more complex logic functions require additional product terms. Another macrocell can be used to supply the required logic resources. However, the MAX 7000B architecture also offers both shareable and parallel expander product terms (“expanders”) that provide additional product terms directly to any macrocell in the same LAB. These expanders help ensure that logic is synthesized with the fewest possible logic resources to obtain the fastest possible speed.

### Shareable Expanders

Each LAB has 16 shareable expanders that can be viewed as a pool of uncommitted single product terms (one from each macrocell) with inverted outputs that feed back into the logic array. Each shareable expander can be used and shared by any or all macrocells in the LAB to build complex logic functions. A small delay ( $t_{SEXP}$ ) is incurred when shareable expanders are used. Figure 3 shows how shareable expanders can feed multiple macrocells.

**Figure 3. MAX 7000B Shareable Expanders**

*Shareable expanders can be shared by any or all macrocells in a LAB.*



### *Parallel Expanders*

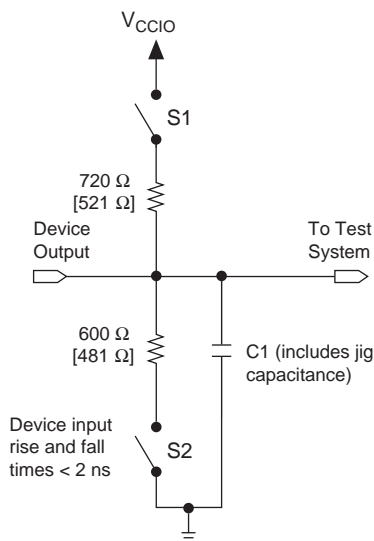
Parallel expanders are unused product terms that can be allocated to a neighboring macrocell to implement fast, complex logic functions. Parallel expanders allow up to 20 product terms to directly feed the macrocell OR logic, with five product terms provided by the macrocell and 15 parallel expanders provided by neighboring macrocells in the LAB.

The Altera Compiler can automatically allocate up to three sets of up to five parallel expanders to the macrocells that require additional product terms. Each set of five parallel expanders incurs a small, incremental timing delay ( $t_{PEXP}$ ). For example, if a macrocell requires 14 product terms, the Compiler uses the five dedicated product terms within the macrocell and allocates two sets of parallel expanders; the first set includes five product terms and the second set includes four product terms, increasing the total delay by  $2 \times t_{PEXP}$ .

Two groups of eight macrocells within each LAB (e.g., macrocells 1 through 8, and 9 through 16) form two chains to lend or borrow parallel expanders. A macrocell borrows parallel expanders from lower-numbered macrocells. For example, macrocell 8 can borrow parallel expanders from macrocell 7, from macrocells 7 and 6, or from macrocells 7, 6, and 5. Within each group of eight, the lowest-numbered macrocell can only lend parallel expanders and the highest-numbered macrocell can only borrow them. [Figure 4](#) shows how parallel expanders can be borrowed from a neighboring macrocell.

**Figure 11. MAX 7000B AC Test Conditions**

Power supply transients can affect AC measurements. Simultaneous transitions of multiple outputs should be avoided for accurate measurement. Threshold tests must not be performed under AC conditions. Large-amplitude, fast-ground-current transients normally occur as the device outputs discharge the load capacitances. When these transients flow through the parasitic inductance between the device ground pin and the test system ground, significant reductions in observable noise immunity can result. Numbers in brackets are for 2.5-V outputs. Numbers without brackets are for 3.3-V outputs. Switches S1 and S2 are open for all tests except output disable timing parameters.



## Operating Conditions

Tables 14 through 17 provide information on absolute maximum ratings, recommended operating conditions, operating conditions, and capacitance for MAX 7000B devices.

**Table 14. MAX 7000B Device Absolute Maximum Ratings** *Note (1)*

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{CCINT}$	Supply voltage		-0.5	3.6	V
$V_{CCIO}$	Supply voltage		-0.5	3.6	V
$V_I$	DC input voltage	(2)	-2.0	4.6	V
$I_{OUT}$	DC output current, per pin		-33	50	mA
$T_{STG}$	Storage temperature	No bias	-65	150	°C
$T_A$	Ambient temperature	Under bias	-65	135	°C
$T_J$	Junction temperature	Under bias	-65	135	°C

**Table 15. MAX 7000B Device Recommended Operating Conditions**

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{CCINT}$	Supply voltage for internal logic and input buffers	(10)	2.375	2.625	V
$V_{CCIO}$	Supply voltage for output drivers, 3.3-V operation		3.0	3.6	V
	Supply voltage for output drivers, 2.5-V operation		2.375	2.625	V
	Supply voltage for output drivers, 1.8-V operation		1.71	1.89	V
$V_{CCISP}$	Supply voltage during in-system programming		2.375	2.625	V
$V_I$	Input voltage	(3)	−0.5	3.9	V
$V_O$	Output voltage		0	$V_{CCIO}$	V
$T_A$	Ambient temperature	For commercial use	0	70	° C
		For industrial use (11)	−40	85	° C
$T_J$	Junction temperature	For commercial use	0	90	° C
		For industrial use (11)	−40	105	° C
$t_R$	Input rise time			40	ns
$t_F$	Input fall time			40	ns

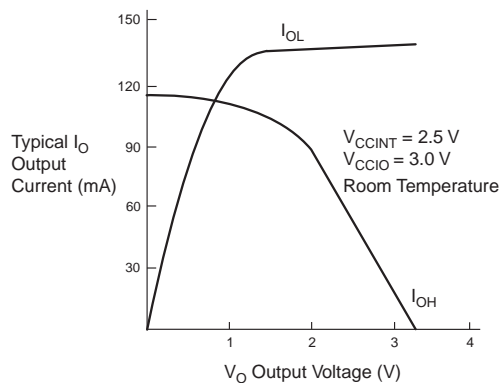
**Table 16. MAX 7000B Device DC Operating Conditions** *Note (4)*

Symbol	Parameter	Conditions	Min	Max	Unit
$V_{IH}$	High-level input voltage for 3.3-V TTL/CMOS		2.0	3.9	V
	High-level input voltage for 2.5-V TTL/CMOS		1.7	3.9	V
	High-level input voltage for 1.8-V TTL/CMOS		$0.65 \times V_{CCIO}$	3.9	V
$V_{IL}$	Low-level input voltage for 3.3-V TTL/CMOS and PCI compliance		-0.5	0.8	V
	Low-level input voltage for 2.5-V TTL/CMOS		-0.5	0.7	V
	Low-level input voltage for 1.8-V TTL/CMOS		-0.5	$0.35 \times V_{CCIO}$	
$V_{OH}$	3.3-V high-level TTL output voltage	$I_{OH} = -8 \text{ mA DC}$ , $V_{CCIO} = 3.00 \text{ V}$ (5)	2.4		V
	3.3-V high-level CMOS output voltage	$I_{OH} = -0.1 \text{ mA DC}$ , $V_{CCIO} = 3.00 \text{ V}$ (5)	$V_{CCIO} - 0.2$		V
	2.5-V high-level output voltage	$I_{OH} = -100 \text{ } \mu\text{A DC}$ , $V_{CCIO} = 2.30 \text{ V}$ (5)	2.1		V
		$I_{OH} = -1 \text{ mA DC}$ , $V_{CCIO} = 2.30 \text{ V}$ (5)	2.0		V
		$I_{OH} = -2 \text{ mA DC}$ , $V_{CCIO} = 2.30 \text{ V}$ (5)	1.7		V
	1.8-V high-level output voltage	$I_{OH} = -2 \text{ mA DC}$ , $V_{CCIO} = 1.65 \text{ V}$ (5)	1.2		V
$V_{OL}$	3.3-V low-level TTL output voltage	$I_{OL} = 8 \text{ mA DC}$ , $V_{CCIO} = 3.00 \text{ V}$ (6)		0.4	V
	3.3-V low-level CMOS output voltage	$I_{OL} = 0.1 \text{ mA DC}$ , $V_{CCIO} = 3.00 \text{ V}$ (6)		0.2	V
	2.5-V low-level output voltage	$I_{OL} = 100 \text{ } \mu\text{A DC}$ , $V_{CCIO} = 2.30 \text{ V}$ (6)		0.2	V
		$I_{OL} = 1 \text{ mA DC}$ , $V_{CCIO} = 2.30 \text{ V}$ (6)		0.4	V
		$I_{OL} = 2 \text{ mA DC}$ , $V_{CCIO} = 2.30 \text{ V}$ (6)		0.7	V
	1.8-V low-level output voltage	$I_{OL} = 2 \text{ mA DC}$ , $V_{CCIO} = 1.7 \text{ V}$ (6)		0.4	V
$I_I$	Input leakage current	$V_I = -0.5 \text{ to } 3.9 \text{ V}$ (7)	-10	10	$\mu\text{A}$
$I_{OZ}$	Tri-state output off-state current	$V_I = -0.5 \text{ to } 3.9 \text{ V}$ (7)	-10	10	$\mu\text{A}$
$R_{ISP}$	Value of I/O pin pull-up resistor during in-system programming or during power up	$V_{CCIO} = 1.7 \text{ to } 3.6 \text{ V}$ (8)	20	74	$k\Omega$

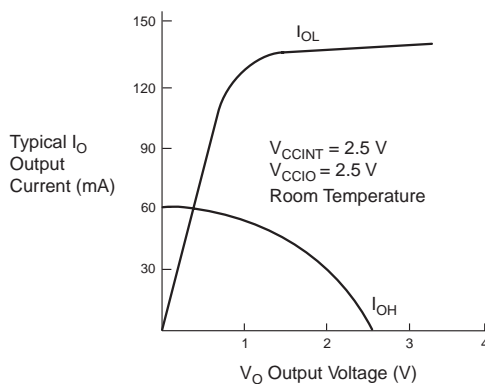
Figure 12 shows the typical output drive characteristics of MAX 7000B devices.

**Figure 12. Output Drive Characteristics of MAX 7000B Devices**

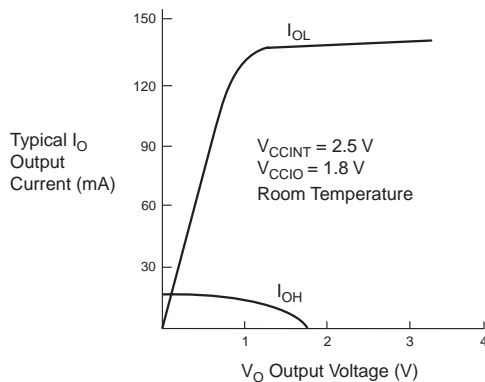
**3.3-V VCCIO**



**2.5-V VCCIO**



**1.8-V VCCIO**





**Table 19. EPM7032B Internal Timing Parameters** *Notes (1)*

Symbol	Parameter	Conditions	Speed Grade						Unit
			-3.5		-5.0		-7.5		
			Min	Max	Min	Max	Min	Max	
$t_{IN}$	Input pad and buffer delay			0.3		0.5		0.7	ns
$t_{IO}$	I/O input pad and buffer delay			0.3		0.5		0.7	ns
$t_{FIN}$	Fast input delay			0.9		1.3		2.0	ns
$t_{FIND}$	Programmable delay adder for fast input			1.0		1.5		1.5	ns
$t_{SEXP}$	Shared expander delay			1.5		2.1		3.2	ns
$t_{PEXP}$	Parallel expander delay			0.4		0.6		0.9	ns
$t_{LAD}$	Logic array delay			1.4		2.0		3.1	ns
$t_{LAC}$	Logic control array delay			1.2		1.7		2.6	ns
$t_{IOE}$	Internal output enable delay			0.1		0.2		0.3	ns
$t_{OD1}$	Output buffer and pad delay slow slew rate = off $V_{CCIO} = 3.3\text{ V}$	$C1 = 35\text{ pF}$		0.9		1.2		1.8	ns
$t_{OD3}$	Output buffer and pad delay slow slew rate = on $V_{CCIO} = 2.5\text{ V}$ or $3.3\text{ V}$	$C1 = 35\text{ pF}$		5.9		6.2		6.8	ns
$t_{ZX1}$	Output buffer enable delay slow slew rate = off $V_{CCIO} = 3.3\text{ V}$	$C1 = 35\text{ pF}$		1.6		2.2		3.4	ns
$t_{ZX3}$	Output buffer enable delay slow slew rate = on $V_{CCIO} = 2.5\text{ V}$ or $3.3\text{ V}$	$C1 = 35\text{ pF}$		6.6		7.2		8.4	ns
$t_{XZ}$	Output buffer disable delay	$C1 = 5\text{ pF}$		1.6		2.2		3.4	ns
$t_{SU}$	Register setup time		0.7		1.1		1.6		ns
$t_H$	Register hold time		0.4		0.5		0.9		ns
$t_{FSU}$	Register setup time of fast input		0.8		0.8		1.1		ns
$t_{FH}$	Register hold time of fast input		1.2		1.2		1.4		ns
$t_{RD}$	Register delay			0.5		0.6		0.9	ns
$t_{COMB}$	Combinatorial delay			0.2		0.3		0.5	ns
$t_{IC}$	Array clock delay			1.2		1.8		2.8	ns
$t_{EN}$	Register enable time			1.2		1.7		2.6	ns
$t_{GLOB}$	Global control delay			0.7		1.1		1.6	ns
$t_{PRE}$	Register preset time			1.0		1.3		1.9	ns
$t_{CLR}$	Register clear time			1.0		1.3		1.9	ns
$t_{PIA}$	PIA delay	(2)		0.7		1.0		1.4	ns
$t_{LPA}$	Low-power adder	(4)		1.5		2.1		3.2	ns

**Table 20. EPM7032B Selectable I/O Standard Timing Adder Delays** *Notes (1)*

I/O Standard	Parameter	Speed Grade						Unit
		-3.5		-5.0		-7.5		
		Min	Max	Min	Max	Min	Max	
PCI	Input to PIA		0.0		0.0		0.0	ns
	Input to global clock and clear		0.0		0.0		0.0	ns
	Input to fast input register		0.0		0.0		0.0	ns
	All outputs		0.0		0.0		0.0	ns

**Notes to tables:**

- (1) These values are specified under the Recommended Operating Conditions in [Table 15 on page 29](#). See [Figure 14](#) for more information on switching waveforms.
- (2) These values are specified for a PIA fan-out of all LABs.
- (3) Measured with a 16-bit loadable, enabled, up/down counter programmed into each LAB.
- (4) The  $t_{LPA}$  parameter must be added to the  $t_{LAD}$ ,  $t_{LAC}$ ,  $t_{IC}$ ,  $t_{ACL}$ ,  $t_{CPW}$ ,  $t_{EN}$ , and  $t_{SEXP}$  parameters for macrocells running in low-power mode.

**Table 22. EPM7064B Internal Timing Parameters** *Note (1)*

Symbol	Parameter	Conditions	Speed Grade						Unit
			-3		-5		-7		
			Min	Max	Min	Max	Min	Max	
$t_{IN}$	Input pad and buffer delay			0.3		0.5		0.7	ns
$t_{IO}$	I/O input pad and buffer delay			0.3		0.5		0.7	ns
$t_{FIN}$	Fast input delay			0.9		1.3		2.0	ns
$t_{FIND}$	Programmable delay adder for fast input			1.0		1.5		1.5	ns
$t_{SEXP}$	Shared expander delay			1.5		2.1		3.2	ns
$t_{PEXP}$	Parallel expander delay			0.4		0.6		0.9	ns
$t_{LAD}$	Logic array delay			1.4		2.0		3.1	ns
$t_{LAC}$	Logic control array delay			1.2		1.7		2.6	ns
$t_{IOE}$	Internal output enable delay			0.1		0.2		0.3	ns
$t_{OD1}$	Output buffer and pad delay slow slew rate = off $V_{CCIO} = 3.3\text{ V}$	$C1 = 35\text{ pF}$		0.9		1.2		1.8	ns
$t_{OD3}$	Output buffer and pad delay slow slew rate = on $V_{CCIO} = 2.5\text{ V}$ or $3.3\text{ V}$	$C1 = 35\text{ pF}$		5.9		6.2		6.8	ns
$t_{ZX1}$	Output buffer enable delay slow slew rate = off $V_{CCIO} = 3.3\text{ V}$	$C1 = 35\text{ pF}$		1.6		2.2		3.4	ns
$t_{ZX3}$	Output buffer enable delay slow slew rate = on $V_{CCIO} = 2.5\text{ V}$ or $3.3\text{ V}$	$C1 = 35\text{ pF}$		6.6		7.2		8.4	ns
$t_{XZ}$	Output buffer disable delay	$C1 = 5\text{ pF}$		1.6		2.2		3.4	ns
$t_{SU}$	Register setup time		0.7		1.1		1.6		ns
$t_H$	Register hold time		0.4		0.5		0.9		ns
$t_{FSU}$	Register setup time of fast input		0.8		0.8		1.1		ns
$t_{FH}$	Register hold time of fast input		1.2		1.2		1.4		ns
$t_{RD}$	Register delay			0.5		0.6		0.9	ns
$t_{COMB}$	Combinatorial delay			0.2		0.3		0.5	ns
$t_{IC}$	Array clock delay			1.2		1.8		2.8	ns
$t_{EN}$	Register enable time			1.2		1.7		2.6	ns
$t_{GLOB}$	Global control delay			0.7		1.1		1.6	ns
$t_{PRE}$	Register preset time			1.0		1.3		1.9	ns
$t_{CLR}$	Register clear time			1.0		1.3		1.9	ns
$t_{PIA}$	PIA delay	(2)		0.7		1.0		1.4	ns
$t_{LPA}$	Low-power adder	(4)		1.5		2.1		3.2	ns

**Table 23. EPM7064B Selectable I/O Standard Timing Adder Delays (Part 2 of 2)** *Note (1)*

I/O Standard	Parameter	Speed Grade						Unit
		-3		-5		-7		
		Min	Max	Min	Max	Min	Max	
PCI	Input to PIA		0.0		0.0		0.0	ns
	Input to global clock and clear		0.0		0.0		0.0	ns
	Input to fast input register		0.0		0.0		0.0	ns
	All outputs		0.0		0.0		0.0	ns

**Notes to tables:**

- (1) These values are specified under the Recommended Operating Conditions in Table 15 on page 29. See Figure 14 for more information on switching waveforms.
- (2) These values are specified for a PIA fan-out of all LABs.
- (3) Measured with a 16-bit loadable, enabled, up/down counter programmed into each LAB.
- (4) The  $t_{LPA}$  parameter must be added to the  $t_{LAD}$ ,  $t_{LAC}$ ,  $t_{IC}$ ,  $t_{ACL}$ ,  $t_{CPPW}$ ,  $t_{EN}$ , and  $t_{SEXP}$  parameters for macrocells running in low-power mode.

Table 24. EPM7128B External Timing Parameters *Note (1)*

Symbol	Parameter	Conditions	Speed Grade						Unit
			-4		-7		-10		
			Min	Max	Min	Max	Min	Max	
t <sub>PD1</sub>	Input to non-registered output	C1 = 35 pF (2)		4.0		7.5		10.0	ns
t <sub>PD2</sub>	I/O input to non-registered output	C1 = 35 pF (2)		4.0		7.5		10.0	ns
t <sub>SU</sub>	Global clock setup time	(2)	2.5		4.5		6.1		ns
t <sub>H</sub>	Global clock hold time	(2)	0.0		0.0		0.0		ns
t <sub>FSU</sub>	Global clock setup time of fast input		1.0		1.5		1.5		ns
t <sub>FH</sub>	Global clock hold time of fast input		1.0		1.0		1.0		ns
t <sub>FZHSU</sub>	Global clock setup time of fast input with zero hold time		2.0		3.0		3.0		ns
t <sub>FZHH</sub>	Global clock hold time of fast input with zero hold time		0.0		0.0		0.0		ns
t <sub>CO1</sub>	Global clock to output delay	C1 = 35 pF	1.0	2.8	1.0	5.7	1.0	7.5	ns
t <sub>CH</sub>	Global clock high time		1.5		3.0		4.0		ns
t <sub>CL</sub>	Global clock low time		1.5		3.0		4.0		ns
t <sub>ASU</sub>	Array clock setup time	(2)	1.2		2.0		2.8		ns
t <sub>AH</sub>	Array clock hold time	(2)	0.2		0.7		0.9		ns
t <sub>ACO1</sub>	Array clock to output delay	C1 = 35 pF (2)	1.0	4.1	1.0	8.2	1.0	10.8	ns
t <sub>ACH</sub>	Array clock high time		1.5		3.0		4.0		ns
t <sub>ACL</sub>	Array clock low time		1.5		3.0		4.0		ns
t <sub>CPPW</sub>	Minimum pulse width for clear and preset		1.5		3.0		4.0		ns
t <sub>CNT</sub>	Minimum global clock period	(2)		4.1		7.9		10.6	ns
f <sub>CNT</sub>	Maximum internal global clock frequency	(2), (3)	243.9		126.6		94.3		MHz
t <sub>ACNT</sub>	Minimum array clock period	(2)		4.1		7.9		10.6	ns
f <sub>ACNT</sub>	Maximum internal array clock frequency	(2), (3)	243.9		126.6		94.3		MHz

**Table 26. EPM7128B Selectable I/O Standard Timing Adder Delays (Part 2 of 2)** *Note (1)*

I/O Standard	Parameter	Speed Grade						Unit
		-4		-7		-10		
		Min	Max	Min	Max	Min	Max	
PCI	Input to PIA		0.0		0.0		0.0	ns
	Input to global clock and clear		0.0		0.0		0.0	ns
	Input to fast input register		0.0		0.0		0.0	ns
	All outputs		0.0		0.0		0.0	ns

**Notes to tables:**

- (1) These values are specified under the Recommended Operating Conditions in Table 15 on page 29. See Figure 14 for more information on switching waveforms.
- (2) These values are specified for a PIA fan-out of one LAB (16 macrocells). For each additional LAB fan-out in these devices, add an additional 0.1 ns to the PIA timing value.
- (3) Measured with a 16-bit loadable, enabled, up/down counter programmed into each LAB.
- (4) The  $t_{LPA}$  parameter must be added to the  $t_{LAD}$ ,  $t_{LAC}$ ,  $t_{IC}$ ,  $t_{ACL}$ ,  $t_{CPW}$ ,  $t_{EN}$ , and  $t_{SEXP}$  parameters for macrocells running in low-power mode.

Table 27. EPM7256B External Timing Parameters *Note (1)*

Symbol	Parameter	Conditions	Speed Grade						Unit
			-5		-7		-10		
			Min	Max	Min	Max	Min	Max	
t <sub>PD1</sub>	Input to non-registered output	C1 = 35 pF (2)		5.0		7.5		10.0	ns
t <sub>PD2</sub>	I/O input to non-registered output	C1 = 35 pF (2)		5.0		7.5		10.0	ns
t <sub>SU</sub>	Global clock setup time	(2)	3.3		4.8		6.6		ns
t <sub>H</sub>	Global clock hold time	(2)	0.0		0.0		0.0		ns
t <sub>FSU</sub>	Global clock setup time of fast input		1.0		1.5		1.5		ns
t <sub>FH</sub>	Global clock hold time for fast input		1.0		1.0		1.0		ns
t <sub>FZHSU</sub>	Global clock setup time of fast input with zero hold time		2.5		3.0		3.0		ns
t <sub>FZHH</sub>	Global clock hold time of fast input with zero hold time		0.0		0.0		0.0		ns
t <sub>CO1</sub>	Global clock to output delay	C1 = 35 pF	1.0	3.3	1.0	5.1	1.0	6.7	ns
t <sub>CH</sub>	Global clock high time		2.0		3.0		4.0		ns
t <sub>CL</sub>	Global clock low time		2.0		3.0		4.0		ns
t <sub>ASU</sub>	Array clock setup time	(2)	1.4		2.0		2.8		ns
t <sub>AH</sub>	Array clock hold time	(2)	0.4		0.8		1.0		ns
t <sub>ACO1</sub>	Array clock to output delay	C1 = 35 pF (2)	1.0	5.2	1.0	7.9	1.0	10.5	ns
t <sub>ACH</sub>	Array clock high time		2.0		3.0		4.0		ns
t <sub>ACL</sub>	Array clock low time		2.0		3.0		4.0		ns
t <sub>CPPW</sub>	Minimum pulse width for clear and preset		2.0		3.0		4.0		ns
t <sub>CNT</sub>	Minimum global clock period	(2)		5.3		7.9		10.6	ns
f <sub>CNT</sub>	Maximum internal global clock frequency	(2), (3)	188.7		126.6		94.3		MHz
t <sub>ACNT</sub>	Minimum array clock period	(2)		5.3		7.9		10.6	ns
f <sub>ACNT</sub>	Maximum internal array clock frequency	(2), (3)	188.7		126.6		94.3		MHz

**Table 28. EPM7256B Internal Timing Parameters** *Note (1)*

Symbol	Parameter	Conditions	Speed Grade						Unit
			-5		-7		-10		
			Min	Max	Min	Max	Min	Max	
$t_{IN}$	Input pad and buffer delay			0.4		0.6		0.8	ns
$t_{IO}$	I/O input pad and buffer delay			0.4		0.6		0.8	ns
$t_{FIN}$	Fast input delay			1.5		2.5		3.1	ns
$t_{FIND}$	Programmable delay adder for fast input			1.5		1.5		1.5	ns
$t_{SEXP}$	Shared expander delay			1.5		2.3		3.0	ns
$t_{PEXP}$	Parallel expander delay			0.4		0.6		0.8	ns
$t_{LAD}$	Logic array delay			1.7		2.5		3.3	ns
$t_{LAC}$	Logic control array delay			1.5		2.2		2.9	ns
$t_{IOE}$	Internal output enable delay			0.1		0.2		0.3	ns
$t_{OD1}$	Output buffer and pad delay slow slew rate = off $V_{CCIO} = 3.3\text{ V}$	$C1 = 35\text{ pF}$		0.9		1.4		1.9	ns
$t_{OD3}$	Output buffer and pad delay slow slew rate = on $V_{CCIO} = 2.5\text{ V}$ or $3.3\text{ V}$	$C1 = 35\text{ pF}$		5.9		6.4		6.9	ns
$t_{ZX1}$	Output buffer enable delay slow slew rate = off $V_{CCIO} = 3.3\text{ V}$	$C1 = 35\text{ pF}$		2.2		3.3		4.5	ns
$t_{ZX3}$	Output buffer enable delay slow slew rate = on $V_{CCIO} = 2.5\text{ V}$ or $3.3\text{ V}$	$C1 = 35\text{ pF}$		7.2		8.3		9.5	ns
$t_{XZ}$	Output buffer disable delay	$C1 = 5\text{ pF}$		2.2		3.3		4.5	ns
$t_{SU}$	Register setup time		1.2		1.8		2.5		ns
$t_H$	Register hold time		0.6		1.0		1.3		ns
$t_{FSU}$	Register setup time of fast input		0.8		1.1		1.1		ns
$t_{FH}$	Register hold time of fast input		1.2		1.4		1.4		ns
$t_{RD}$	Register delay			0.7		1.0		1.3	ns
$t_{COMB}$	Combinatorial delay			0.3		0.4		0.5	ns
$t_{IC}$	Array clock delay			1.5		2.3		3.0	ns
$t_{EN}$	Register enable time			1.5		2.2		2.9	ns
$t_{GLOB}$	Global control delay			1.3		2.1		2.7	ns
$t_{PRE}$	Register preset time			1.0		1.6		2.1	ns
$t_{CLR}$	Register clear time			1.0		1.6		2.1	ns
$t_{PIA}$	PIA delay	(2)		1.7		2.6		3.3	ns
$t_{LPA}$	Low-power adder	(4)		2.0		3.0		4.0	ns



**Table 29. EPM7256B Selectable I/O Standard Timing Adder Delays (Part 1 of 2)** *Note (1)*

I/O Standard	Parameter	Speed Grade						Unit
		-5		-7		-10		
		Min	Max	Min	Max	Min	Max	
3.3 V TTL/CMOS	Input to PIA		0.0		0.0		0.0	ns
	Input to global clock and clear		0.0		0.0		0.0	ns
	Input to fast input register		0.0		0.0		0.0	ns
	All outputs		0.0		0.0		0.0	ns
2.5 V TTL/CMOS	Input to PIA		0.4		0.6		0.8	ns
	Input to global clock and clear		0.3		0.5		0.6	ns
	Input to fast input register		0.2		0.3		0.4	ns
	All outputs		0.2		0.3		0.4	ns
1.8 V TTL/CMOS	Input to PIA		0.6		0.9		1.2	ns
	Input to global clock and clear		0.6		0.9		1.2	ns
	Input to fast input register		0.5		0.8		1.0	ns
	All outputs		1.3		2.0		2.6	ns
SSTL-2 Class I	Input to PIA		1.5		2.3		3.0	ns
	Input to global clock and clear		1.3		2.0		2.6	ns
	Input to fast input register		1.1		1.7		2.2	ns
	All outputs		0.0		0.0		0.0	ns
SSTL-2 Class II	Input to PIA		1.5		2.3		3.0	ns
	Input to global clock and clear		1.3		2.0		2.6	ns
	Input to fast input register		1.1		1.7		2.2	ns
	All outputs		−0.1		−0.2		−0.2	ns
SSTL-3 Class I	Input to PIA		1.4		2.1		2.8	ns
	Input to global clock and clear		1.1		1.7		2.2	ns
	Input to fast input register		1.0		1.5		2.0	ns
	All outputs		0.0		0.0		0.0	ns
SSTL-3 Class II	Input to PIA		1.4		2.1		2.8	ns
	Input to global clock and clear		1.1		1.7		2.2	ns
	Input to fast input register		1.0		1.5		2.0	ns
	All outputs		0.0		0.0		0.0	ns
GTL+	Input to PIA		1.8		2.7		3.6	ns
	Input to global clock and clear		1.8		2.7		3.6	ns
	Input to fast input register		1.7		2.6		3.4	ns
	All outputs		0.0		0.0		0.0	ns

Table 30. EPM7512B External Timing Parameters *Note (1)*

Symbol	Parameter	Conditions	Speed Grade						Unit
			-5		-7		-10		
			Min	Max	Min	Max	Min	Max	
t <sub>PD1</sub>	Input to non-registered output	C1 = 35 pF (2)		5.5		7.5		10.0	ns
t <sub>PD2</sub>	I/O input to non-registered output	C1 = 35 pF (2)		5.5		7.5		10.0	ns
t <sub>SU</sub>	Global clock setup time	(2)	3.6		4.9		6.5		ns
t <sub>H</sub>	Global clock hold time	(2)	0.0		0.0		0.0		ns
t <sub>FSU</sub>	Global clock setup time of fast input		1.0		1.5		1.5		ns
t <sub>FH</sub>	Global clock hold time of fast input		1.0		1.0		1.0		ns
t <sub>FZHSU</sub>	Global clock setup time of fast input with zero hold time		2.5		3.0		3.0		ns
t <sub>FZHH</sub>	Global clock hold time of fast input with zero hold time		0.0		0.0		0.0		ns
t <sub>CO1</sub>	Global clock to output delay	C1 = 35 pF	1.0	3.7	1.0	5.0	1.0	6.7	ns
t <sub>CH</sub>	Global clock high time		3.0		3.0		4.0		ns
t <sub>CL</sub>	Global clock low time		3.0		3.0		4.0		ns
t <sub>ASU</sub>	Array clock setup time	(2)	1.4		1.9		2.5		ns
t <sub>AH</sub>	Array clock hold time	(2)	0.5		0.6		0.8		ns
t <sub>ACO1</sub>	Array clock to output delay	C1 = 35 pF (2)	1.0	5.9	1.0	8.0	1.0	10.7	ns
t <sub>ACH</sub>	Array clock high time		3.0		3.0		4.0		ns
t <sub>ACL</sub>	Array clock low time		3.0		3.0		4.0		ns
t <sub>CPPW</sub>	Minimum pulse width for clear and preset		3.0		3.0		4.0		ns
t <sub>CNT</sub>	Minimum global clock period	(2)		6.1		8.4		11.1	ns
f <sub>CNT</sub>	Maximum internal global clock frequency	(2), (3)	163.9		119.0		90.1		MHz
t <sub>ACNT</sub>	Minimum array clock period	(2)		6.1		8.4		11.1	ns
f <sub>ACNT</sub>	Maximum internal array clock frequency	(2), (3)	163.9		119.0		90.1		MHz

**Table 32. EPM7512B Selectable I/O Standard Timing Adder Delays (Part 2 of 2)** *Note (1)*

I/O Standard	Parameter	Speed Grade						Unit
		-5		-7		-10		
		Min	Max	Min	Max	Min	Max	
PCI	Input to PIA		0.0		0.0		0.0	ns
	Input to global clock and clear		0.0		0.0		0.0	ns
	Input to fast input register		0.0		0.0		0.0	ns
	All outputs		0.0		0.0		0.0	ns

**Notes to tables:**

- (1) These values are specified under the Recommended Operating Conditions in Table 15 on page 29. See Figure 14 for more information on switching waveforms.
- (2) These values are specified for a PIA fan-out of one LAB (16 macrocells). For each additional LAB fan-out in these devices, add an additional 0.12 ns to the PIA timing value.
- (3) Measured with a 16-bit loadable, enabled, up/down counter programmed into each LAB.
- (4) The  $t_{LPA}$  parameter must be added to the  $t_{LAD}$ ,  $t_{LAC}$ ,  $t_{IC}$ ,  $t_{ACL}$ ,  $t_{CPW}$ ,  $t_{EN}$ , and  $t_{SEXP}$  parameters for macrocells running in low-power mode.

## Power Consumption

Supply power (P) versus frequency ( $f_{MAX}$ , in MHz) for MAX 7000B devices is calculated with the following equation:

$$P = P_{INT} + P_{IO} = I_{CCINT} \times V_{CC} + P_{IO}$$

The  $P_{IO}$  value, which depends on the device output load characteristics and switching frequency, can be calculated using the guidelines given in Application Note 74 (*Evaluating Power for Altera Devices*).

The  $I_{CCINT}$  value depends on the switching frequency and the application logic. The  $I_{CCINT}$  value is calculated with the following equation:

$$I_{CCINT} =$$

$$(A \times MC_{TON}) + [B \times (MC_{DEV} - MC_{TON})] + (C \times MC_{USED} \times f_{MAX} \times \log_{LC})$$

The parameters in this equation are:

$MC_{TON}$  = Number of macrocells with the Turbo Bit™ option turned on, as reported in the MAX+PLUS II Report File (.rpt)

$MC_{DEV}$  = Number of macrocells in the device

$MC_{USED}$  = Total number of macrocells in the design, as reported in the Report File

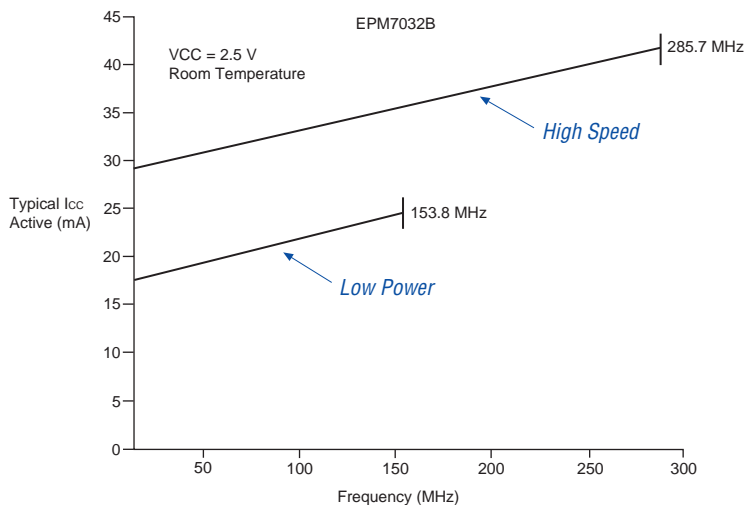
$f_{MAX}$  = Highest clock frequency to the device

$\log_{LC}$  = Average percentage of logic cells toggling at each clock (typically 12.5%)

A, B, C = Constants, shown in [Table 33](#)

<b>Table 33. MAX 7000B <math>I_{CC}</math> Equation Constants</b>			
<b>Device</b>	<b>A</b>	<b>B</b>	<b>C</b>
EPM7032B	0.91	0.54	0.010
EPM7064B	0.91	0.54	0.012
EPM7128B	0.91	0.54	0.016
EPM7256B	0.91	0.54	0.017
EPM7512B	0.91	0.54	0.019

This calculation provides an  $I_{CC}$  estimate based on typical conditions using a pattern of a 16-bit, loadable, enabled, up/down counter in each LAB with no output load. Actual  $I_{CC}$  should be verified during operation because this measurement is sensitive to the actual pattern in the device and the environmental operating conditions.

**Figure 15.  $I_{CC}$  vs. Frequency for EPM7032B Devices****Figure 16.  $I_{CC}$  vs. Frequency for EPM7064B Devices**